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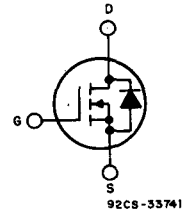
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N-Channel Logic Level Power Field-Effect Transistors (L² FET)

12 A, 80 V and 100 V
 $r_{DS(On)}$: 0.2 Ω

Features:

- Design optimized for 5 volt gate drive
- Can be driven directly from Q-MOS, N-MOS, TTL Circuits
- Compatible with automotive drive requirements
- SOA is power-dissipation limited
- Nanosecond switching speeds
- Linear transfer characteristics
- High input impedance
- Majority carrier device



N-CHANNEL ENHANCEMENT MODE

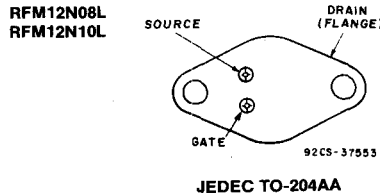
The RFM12N08L and RFM12N10L and the RFP12N08L and RFP12N10L* are n-channel enhancement-mode silicon-gate power field-effect transistors specifically designed for use with logic level (5 volt) driving sources in applications such as programmable controllers, automotive switching, and solenoid drivers. This performance is accomplished through a special gate oxide design which provides full rated conduction at gate biases in the 3-5 volt range, thereby facilitating true on-off power control directly from logic circuit supply voltages.

The RFM-series types are supplied in the JEDEC TO-204AA steel package and the RFP-series types in the JEDEC TO-220AB plastic package.

Because of space limitations branding (marking) on type RFP12N08L is F12N08L and on type RFP12N10L is F12N10L.

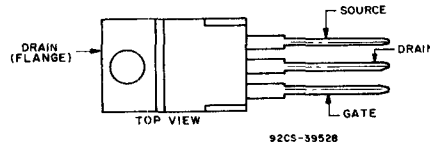
*The RFM and RFP series were formerly RCA developmental number TA9526 and TA9527.

TERMINAL DESIGNATIONS



JEDEC TO-204AA

RFP12N08L
RFP12N10L



JEDEC TO-220AB

MAXIMUM RATINGS, Absolute-Maximum Values (T_c=25° C):

	RFM12N08L	RFM12N10L		RFP12N08L	RFP12N10L	
DRAIN-SOURCE VOLTAGE V _{DSS}	80	100		80	100	V
DRAIN-GATE VOLTAGE (R _{gs} =1 M Ω) V _{DGR}	80	100		80	100	V
GATE-SOURCE VOLTAGE V _{GS}	_____		±10	_____		V
DRAIN CURRENT, RMS Continuous I _D	_____		12	_____		A
Pulsed I _{DM}	_____		30	_____		A
POWER DISSIPATION @ T _c =25° C P _T	75	75		60	60	W
Derate above T _c =25° C	0.6	0.6		0.48	0.48	W/°C
OPERATING AND STORAGE						
TEMPERATURE T _j , T _{sup}	_____		-55 to +150	_____		°C

RFM12N08L, RFM12N10L, RFP12N08L, RFP12N10L
ELECTRICAL CHARACTERISTICS, At Case Temperature (T_C)=25°C unless otherwise specified.

CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS				UNITS
			RFM12N08L RFP12N08L		RFM12N10L RFP12N10L		
			MIN.	MAX.	MIN.	MAX.	
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D=1\text{ mA}$ $V_{GS}=0$	80	—	100	—	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}$ $I_D=1\text{ mA}$	1	2	1	2	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=65\text{ V}$ $V_{GS}=80\text{ V}$	—	1	—	—	μA
		$T_C=125^\circ\text{C}$ $V_{DS}=65\text{ V}$ $V_{GS}=80\text{ V}$	—	50	—	—	
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 10\text{ V}$ $V_{DS}=0$	—	100	—	100	nA
Drain-Source On Voltage	$V_{DS(on)}^a$	$I_D=6\text{ A}$ $V_{GS}=5\text{ V}$	—	1.2	—	1.2	V
		$I_D=12\text{ A}$ $V_{GS}=5\text{ V}$	—	3.3	—	3.3	
Static Drain-Source On Resistance	$r_{DS(on)}^a$	$I_D=6\text{ A}$ $V_{GS}=5\text{ V}$	—	0.2	—	0.2	Ω
Forward Transconductance	g_s^a	$V_{DS}=10\text{ V}$ $I_D=6\text{ A}$	4.0	—	4.0	—	mho
Input Capacitance	C_{iss}	$V_{DS}=25\text{ V}$	—	900	—	900	pF
Output Capacitance	C_{oss}	$V_{GS}=0\text{ V}$	—	325	—	325	
Reverse-Transfer Capacitance	C_{rss}	$f=1\text{ MHz}$	—	170	—	170	
Turn-On Delay Time	$t_d(on)$	$V_{DD}=50\text{ V}$ $I_D=6\text{ A}$ $R_{gen}=\infty$ $R_{gs}=6.25\ \Omega$ $V_{GS}=5\text{ V}$	15(typ)	50	15(typ)	50	ns
Rise Time	t_r		70(typ)	150	70(typ)	150	
Turn-Off Delay Time	$t_d(off)$		100(typ)	130	100(typ)	130	
Fall Time	t_f		80(typ)	150	80(typ)	150	
Thermal Resistance Junction-to-Case	$R\theta_{JC}$		RFM12N08L, RFM12N10L	—	1.67	—	
		RFP12N08L, RFP12N10L	—	2.083	—	2.083	

^aPulsed: Pulse duration = 300 μs max., duty cycle = 2%.

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS				UNITS
			RFM12N08L RFP12N08L		RFM12N10L RFP12N10L		
			MIN.	MAX.	MIN.	MAX.	
Diode Forward Voltage	V_{SD}	$I_{SD}=6\text{ A}$	—	1.4	—	1.4	V
Reverse Recovery Time	t_{rr}	$I_F=4\text{ A}$ $d_I/d_t=100\text{ A}/\mu\text{s}$	150(typ)		150(typ)		ns

^{*}Pulse Test: Width $\leq 300\ \mu\text{s}$, duty cycle $\leq 2\%$.

RFM12N08L, RFM12N10L, RFP12N08L, RFP12N10L

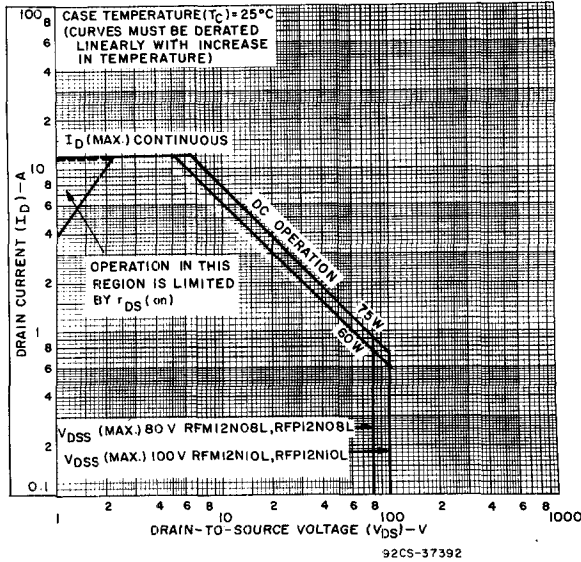


Fig. 1 — Maximum operating areas for all types.

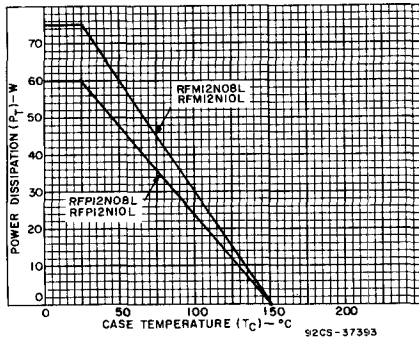


Fig. 2 — Power dissipation vs. temperature derating curve for all types.

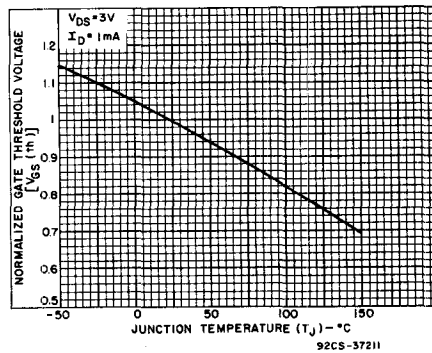


Fig. 3 — Typical normalized gate threshold voltage as a function of junction temperature for all types.

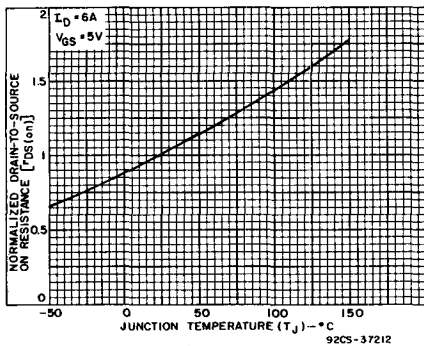


Fig. 4 — Normalized drain-to-source on resistance to junction temperature for all types.

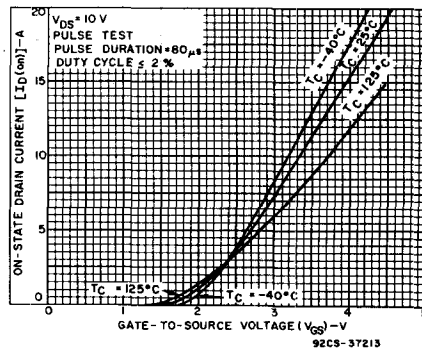


Fig. 5 — Typical transfer characteristics for all types.

RFM12N08L, RFM12N10L, RFP12N08L, RFP12N10L

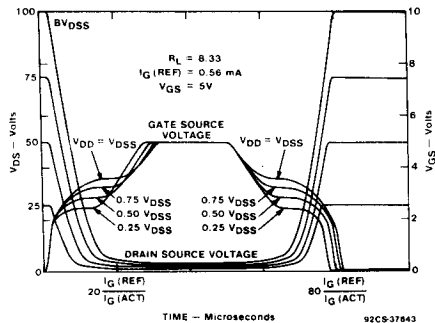


Fig. 6 - Normalized switching waveforms for constant gate-current. Refer to RCA application notes AN-7254 and AN-7260.

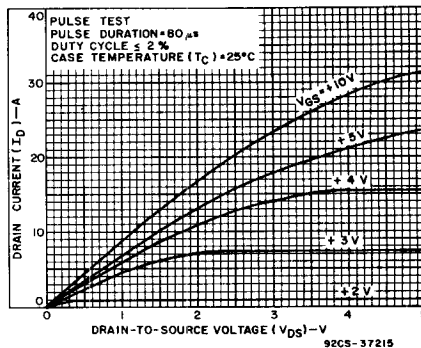


Fig. 7 — Typical saturation characteristics for all types.

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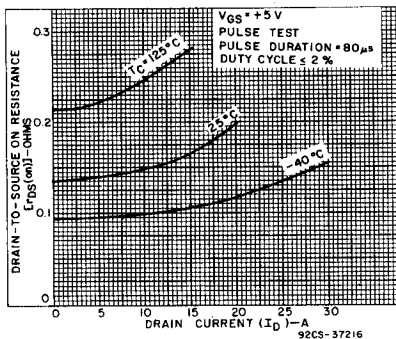


Fig. 8 — Typical drain-to-source on resistance as a function of drain current for all types.

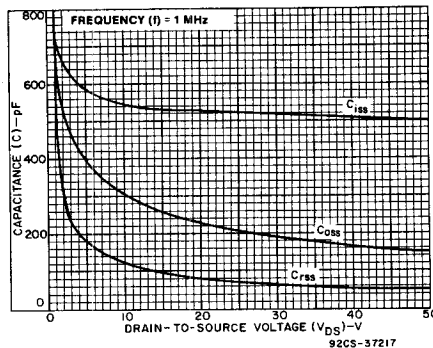


Fig. 9 — Capacitance as a function of drain-to-source voltage for all types.

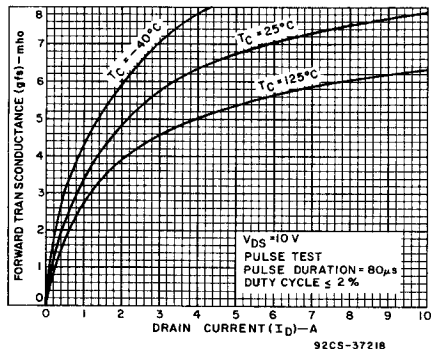


Fig. 10 — Typical forward transconductance as a function of drain current for all types.

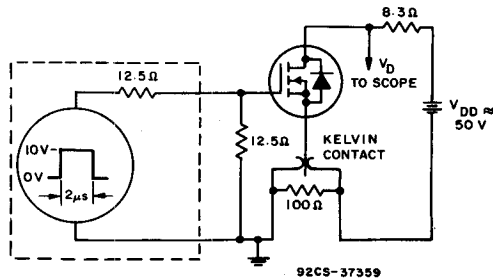


Fig. 11 — Switching Time Test Circuit.